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### **CONTENTS**

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The article presents an overview of the activities of the Institute of Physical Engineering (Faculty of Mechanical Engineering, Brno University of Technology) in building a Central European Institute of Technology which brings together scientists from several Brno universities and research institutions. The Institute staff is involved in the preparation, implementation and coordination of research, especially in the field of material sciences and nanotechnology.

### Application of scanning near field optical microscope for plasmonics (L. Břínek, P. Dvořák, T. Neuman, T. Šamořil, P. Dub,

scanning near field optical microscope. Interference patterns of surface plasmon polaritons have been measured between pairs of excitation grooves fabricated by the focused ion beam on the metallic surface. Interference patters in the space among excitation grooves depend on the mutual angle between the grooves and the polarization state of the incident electromagnetic field.

### Coherence-controlled holographic microscope and its application at IPE BUT (A. Křížová, J. Čolláková, R. Chmelík).......171

Coherence-controlled holographic microscope was developed and designed at IPE BUT. This technique uses off-axis holography in connection with achromatic interferometer. Advantages of this method are quantitative phase imaging, image reconstruction from one hologram, imaging through turbid media and numerical refocusing. Next basic biological applications such as long-term observation of living cells, monitoring of cell reactions to external stimuli, and imaging cells in turbid media, which this technique is advantageous to use for, are shown in the article.

### Incubation device for living cells observation in coherence-controlled holographic microscope

### Mobile apparatus for remote material analysis by laser induced breakdown spectroscopy

**Keywords:** LIBS, spectroscopy, laser, plasma, stand-off, remote analysis

## Inspection of optical fiber connector dimensions by means of computed tomography

In this paper we present the utilization possibilities of X-ray computed tomography with high spatial resolution – X-ray microtomography ( $\mu$ CT). For demonstrating the possibilities of  $\mu$ CT, an analysis of an F-SMA standard SMA connector (SMA 905, Type 1) employed in the setup for Laser-Induced Breakdown Spectroscopy (LIBS) was carried out.

**Keywords:** computed tomography, CT, μCT, SMA connector

Characterization methods of graphene (Z. Lišková, P. Procházka, M. Bartošík, J. Mach, M. Urbánek, T. Šikola, M. Ledinský, A. Fejfar) ... 184 Graphene, a monolayer of carbon atoms arranged in a hexagonal grid, has been during the last decade an object of great interest to scientists for its unique mechanical, electronic and magnetic properties both in terms of theory and application. This article discusses the methods of graphene preparation by the mechanical exfoliation and chemical vapour deposition (CVD). At the same time the attention is focused on the characterization of graphene films using optical microscopy, reflectometry, micro-Raman spectroscopy and atomic force microscopy (AFM), which are essential in determining the quality of graphene layers and improving their preparation. Keywords: graphen, mechanical exfoliation of graphit, CVD graphen, Raman spectroscopy, reflectometry, AFM

#### Device for analysis of silicon wafers

**Keywords:** silicon wafer, Czochralski method, defect analysis, OISF test, positioning *xy* table, image analysis

#### System for characterization and optimization of piezoactuators

**Keywords:** piezo, stepper motor, interferometer, piezoactuator optimization, LabVIEW

**Keywords:** Rayleigh's surface wave, physical conditions, electromagnetic

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Probably the biggest conference that involves advanced microscopic methods Focus on Microscopy was hold in Maastricht in March 24 - 27, 2013. There was presented over 440 contributions in the form of invited and standard oral presentations and posters. The newest available technologies were introduced by more than 50 companies, the main sponsor was German company Leica Microsystems GmbH oriented on the most advanced techniques in the optical microscopy.

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